Applicant(s)/Patent Under Reexamination 10/087,204 WANG ET AL. Notice of References Cited Art Unit Examiner

Etienne P LeRoux

Application/Control No.

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,061,680	05-2000	Scherf et al.	707/3
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